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(71)Applicant : SANYO ELECTRIC CO LTD

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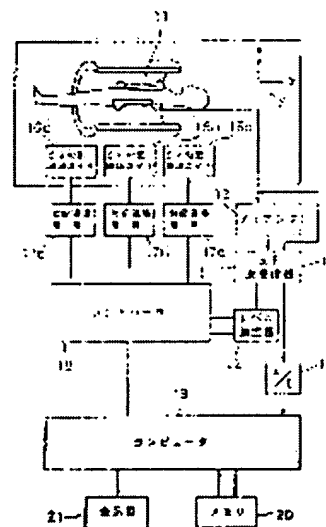
(72)Inventor : ANDO TAKAHISA
IMAZATO ISAO

(54) RECEIVING SENSITIVITY ADJUSTING DEVICE FOR NMR SIGNAL USED FOR MAGNETIC RESONANCE PHOTOGRAPHING DEVICE

(57)Abstract:

PURPOSE: To eliminate deterioration of the picture quality and obtain an excellent dislocation image of it by varying the phase encode gradient magnetic field in an area around $G_{\phi}=0$, measuring corresponding NMR signals, and by adjusting the signal receiving gain of NMR signal on the basis of the NMR signal with max. intensity.

CONSTITUTION: The phase encode gradient magnetic field G_{ϕ} is varied with the size varied near $G_{\phi}=0$, and the sequence is repeated. The NMR signal obtained is amplified by a preamplifier 13 and an RF transmitter/receiver 14, and the level is measured by a level measuring instrument 22. A controller 18 stores the max. level, and the reception level of the RF transmitter/receiver 14 is adjusted so that this stored max. level becomes the allowable input level for an A/D converter 15. Because the reception gain of the RF transmitter/receiver 14 has been adjusted in this fashion at the time of photographing the NMR dislocation, the NMR signal can always be maintained so as not to exceed the allowable input value for the A/D converter. Accordingly two-dimensional Fourier transform is made on the basis of signal by the sequence, which enables producing an excellent dislocation image.



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